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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

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Details

Product Status	Obsolete
Core Processor	XC800
Core Size	8-Bit
Speed	24MHz
Connectivity	SSI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	48
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	1.75K x 8
Voltage - Supply (Vcc/Vdd)	4.5V ~ 5.5V
Data Converters	A/D 8x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	PG-TQFP-64
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/saf-xc888-8ffa-5v-ac

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General Device Information
Table 3 Pin Definitions and Functions (cont'd)

Symbol	Pin Number (TQFP-48/64)	Type	Reset State	Function
P3.7	34/42		Hi-Z	EXINT4 External Interrupt Input 4 COUT63_0 Output of Capture/Compare channel 3

Functional Description
Table 8 SCU Register Overview (cont'd)

Addr	Register Name	Bit	7	6	5	4	3	2	1	0
BC _H	NMISR Reset: 00_H NMI Status Register	Bit Field	0	FNMI ECC	FNMI VDDP	FNMI VDD	FNMI OCDS	FNMI FLASH	FNMI PLL	FNMI WDT
		Type	r	rwh	rwh	rwh	rwh	rwh	rwh	rwh
BD _H	BCON Reset: 00_H Baud Rate Control Register	Bit Field	BGSEL		0	BRDIS	BRPRE			R
		Type	rw		r	rw	rw			rw
BE _H	BG Reset: 00_H Baud Rate Timer/Reload Register	Bit Field	BR_VALUE							
		Type	rwh							
E9 _H	FDCON Reset: 00_H Fractional Divider Control Register	Bit Field	BGS	SYNE N	ERRS YN	EOFS YN	BRK	NDOV	FDM	FDEN
		Type	rw	rw	rwh	rwh	rwh	rwh	rw	rw
EA _H	FDSTEP Reset: 00_H Fractional Divider Reload Register	Bit Field	STEP							
		Type	rw							
EB _H	FDRES Reset: 00_H Fractional Divider Result Register	Bit Field	RESULT							
		Type	rh							
RMAP = 0, PAGE 1										
B3 _H	ID Reset: UU_H Identity Register	Bit Field	PRODID					VERID		
		Type	r					r		
B4 _H	PMCON0 Reset: 00_H Power Mode Control Register 0	Bit Field	0	WDT RST	WKRS	WK SEL	SD	PD	WS	
		Type	r	rwh	rwh	rw	rw	rwh	rw	
B5 _H	PMCON1 Reset: 00_H Power Mode Control Register 1	Bit Field	0	CDC_ DIS	CAN_ DIS	MDU_ DIS	T2_ DIS	CCU_ DIS	SSC_ DIS	ADC_ DIS
		Type	r	rw	rw	rw	rw	rw	rw	rw
B6 _H	OSC_CON Reset: 08_H OSC Control Register	Bit Field	0			OSC PD	XPD	OSC SS	ORD RES	OSCR
		Type	r			rw	rw	rw	rwh	rh
B7 _H	PLL_CON Reset: 90_H PLL Control Register	Bit Field	NDIV				VCO BYP	OSC DISC	RESL D	LOCK
		Type	rw				rw	rw	rwh	rh
BA _H	CMCON Reset: 10_H Clock Control Register	Bit Field	VCO SEL	KDIV	0	FCCF G	CLKREL			
		Type	rw	rw	r	rw	rw			
BB _H	PASSWD Reset: 07_H Password Register	Bit Field	PASS					PROT ECT_S	MODE	
		Type	wh					rh	rw	
BC _H	FEAL Reset: 00_H Flash Error Address Register Low	Bit Field	ECCERRADDR							
		Type	rh							
BD _H	FEAH Reset: 00_H Flash Error Address Register High	Bit Field	ECCERRADDR							
		Type	rh							

Functional Description
Table 10 Port Register Overview (cont'd)

Addr	Register Name	Bit	7	6	5	4	3	2	1	0
RMAP = 0, PAGE 1										
80 _H	P0_PUDSEL Reset: FF_H P0 Pull-Up/Pull-Down Select Register	Bit Field	P7	P6	P5	P4	P3	P2	P1	P0
		Type	rw	rw	rw	rw	rw	rw	rw	rw
86 _H	P0_PUDEN Reset: C4_H P0 Pull-Up/Pull-Down Enable Register	Bit Field	P7	P6	P5	P4	P3	P2	P1	P0
		Type	rw	rw	rw	rw	rw	rw	rw	rw
90 _H	P1_PUDSEL Reset: FF_H P1 Pull-Up/Pull-Down Select Register	Bit Field	P7	P6	P5	P4	P3	P2	P1	P0
		Type	rw	rw	rw	rw	rw	rw	rw	rw
91 _H	P1_PUDEN Reset: FF_H P1 Pull-Up/Pull-Down Enable Register	Bit Field	P7	P6	P5	P4	P3	P2	P1	P0
		Type	rw	rw	rw	rw	rw	rw	rw	rw
92 _H	P5_PUDSEL Reset: FF_H P5 Pull-Up/Pull-Down Select Register	Bit Field	P7	P6	P5	P4	P3	P2	P1	P0
		Type	rw	rw	rw	rw	rw	rw	rw	rw
93 _H	P5_PUDEN Reset: FF_H P5 Pull-Up/Pull-Down Enable Register	Bit Field	P7	P6	P5	P4	P3	P2	P1	P0
		Type	rw	rw	rw	rw	rw	rw	rw	rw
A0 _H	P2_PUDSEL Reset: FF_H P2 Pull-Up/Pull-Down Select Register	Bit Field	P7	P6	P5	P4	P3	P2	P1	P0
		Type	rw	rw	rw	rw	rw	rw	rw	rw
A1 _H	P2_PUDEN Reset: 00_H P2 Pull-Up/Pull-Down Enable Register	Bit Field	P7	P6	P5	P4	P3	P2	P1	P0
		Type	rw	rw	rw	rw	rw	rw	rw	rw
B0 _H	P3_PUDSEL Reset: BF_H P3 Pull-Up/Pull-Down Select Register	Bit Field	P7	P6	P5	P4	P3	P2	P1	P0
		Type	rw	rw	rw	rw	rw	rw	rw	rw
B1 _H	P3_PUDEN Reset: 40_H P3 Pull-Up/Pull-Down Enable Register	Bit Field	P7	P6	P5	P4	P3	P2	P1	P0
		Type	rw	rw	rw	rw	rw	rw	rw	rw
C8 _H	P4_PUDSEL Reset: FF_H P4 Pull-Up/Pull-Down Select Register	Bit Field	P7	P6	P5	P4	P3	P2	P1	P0
		Type	rw	rw	rw	rw	rw	rw	rw	rw
C9 _H	P4_PUDEN Reset: 04_H P4 Pull-Up/Pull-Down Enable Register	Bit Field	P7	P6	P5	P4	P3	P2	P1	P0
		Type	rw	rw	rw	rw	rw	rw	rw	rw
RMAP = 0, PAGE 2										
80 _H	P0_ALTSEL0 Reset: 00_H P0 Alternate Select 0 Register	Bit Field	P7	P6	P5	P4	P3	P2	P1	P0
		Type	rw	rw	rw	rw	rw	rw	rw	rw
86 _H	P0_ALTSEL1 Reset: 00_H P0 Alternate Select 1 Register	Bit Field	P7	P6	P5	P4	P3	P2	P1	P0
		Type	rw	rw	rw	rw	rw	rw	rw	rw
90 _H	P1_ALTSEL0 Reset: 00_H P1 Alternate Select 0 Register	Bit Field	P7	P6	P5	P4	P3	P2	P1	P0
		Type	rw	rw	rw	rw	rw	rw	rw	rw
91 _H	P1_ALTSEL1 Reset: 00_H P1 Alternate Select 1 Register	Bit Field	P7	P6	P5	P4	P3	P2	P1	P0
		Type	rw	rw	rw	rw	rw	rw	rw	rw
92 _H	P5_ALTSEL0 Reset: 00_H P5 Alternate Select 0 Register	Bit Field	P7	P6	P5	P4	P3	P2	P1	P0
		Type	rw	rw	rw	rw	rw	rw	rw	rw

Functional Description

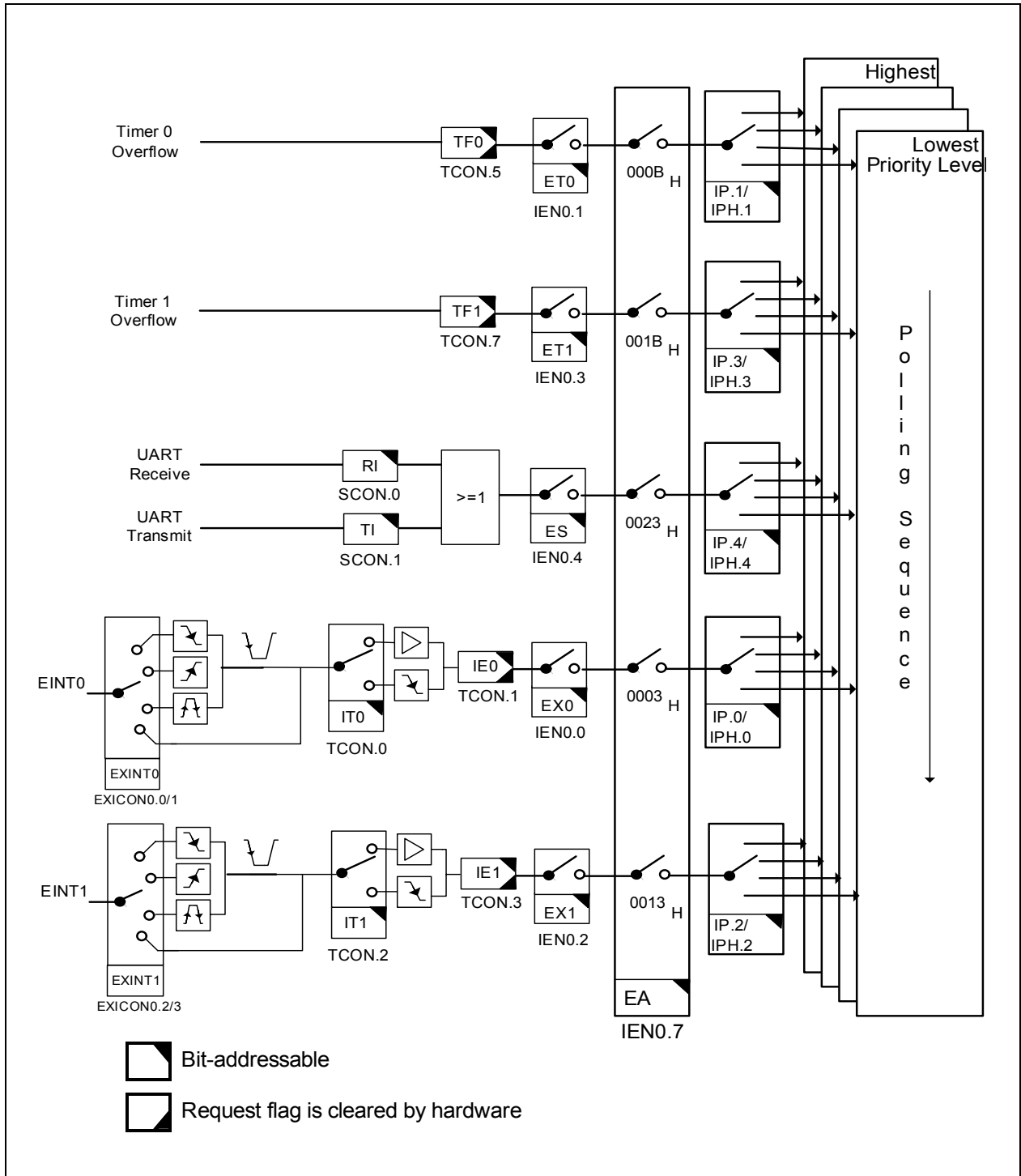


Figure 14 Interrupt Request Sources (Part 1)

Functional Description

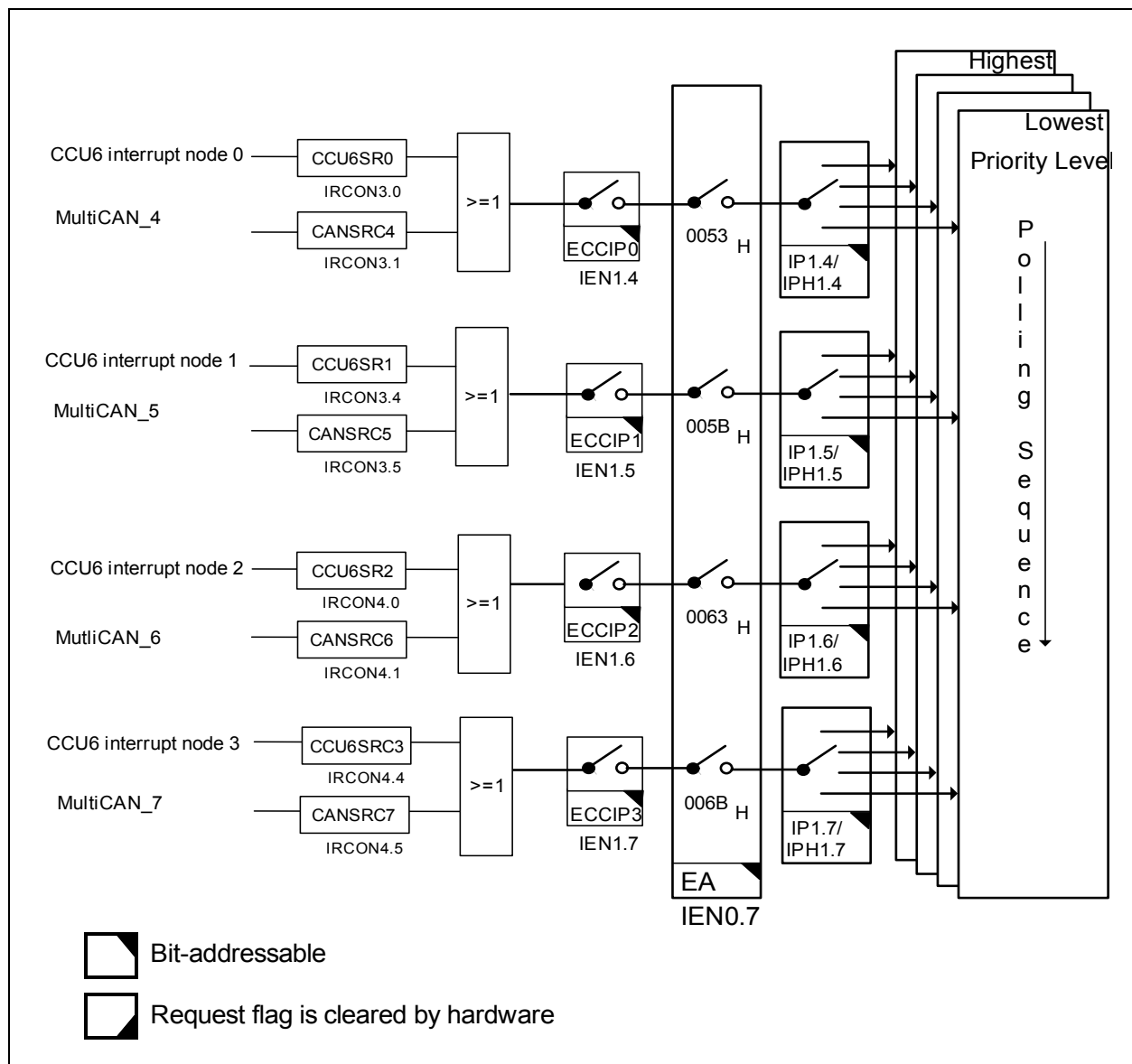


Figure 18 Interrupt Request Sources (Part 5)

Functional Description

3.6 Power Supply System with Embedded Voltage Regulator

The XC886/888 microcontroller requires two different levels of power supply:

- 3.3 V or 5.0 V for the Embedded Voltage Regulator (EVR) and Ports
- 2.5 V for the core, memory, on-chip oscillator, and peripherals

Figure 21 shows the XC886/888 power supply system. A power supply of 3.3 V or 5.0 V must be provided from the external power supply pin. The 2.5 V power supply for the logic is generated by the EVR. The EVR helps to reduce the power consumption of the whole chip and the complexity of the application board design.

The EVR consists of a main voltage regulator and a low power voltage regulator. In active mode, both voltage regulators are enabled. In power-down mode, the main voltage regulator is switched off, while the low power voltage regulator continues to function and provide power supply to the system with low power consumption.

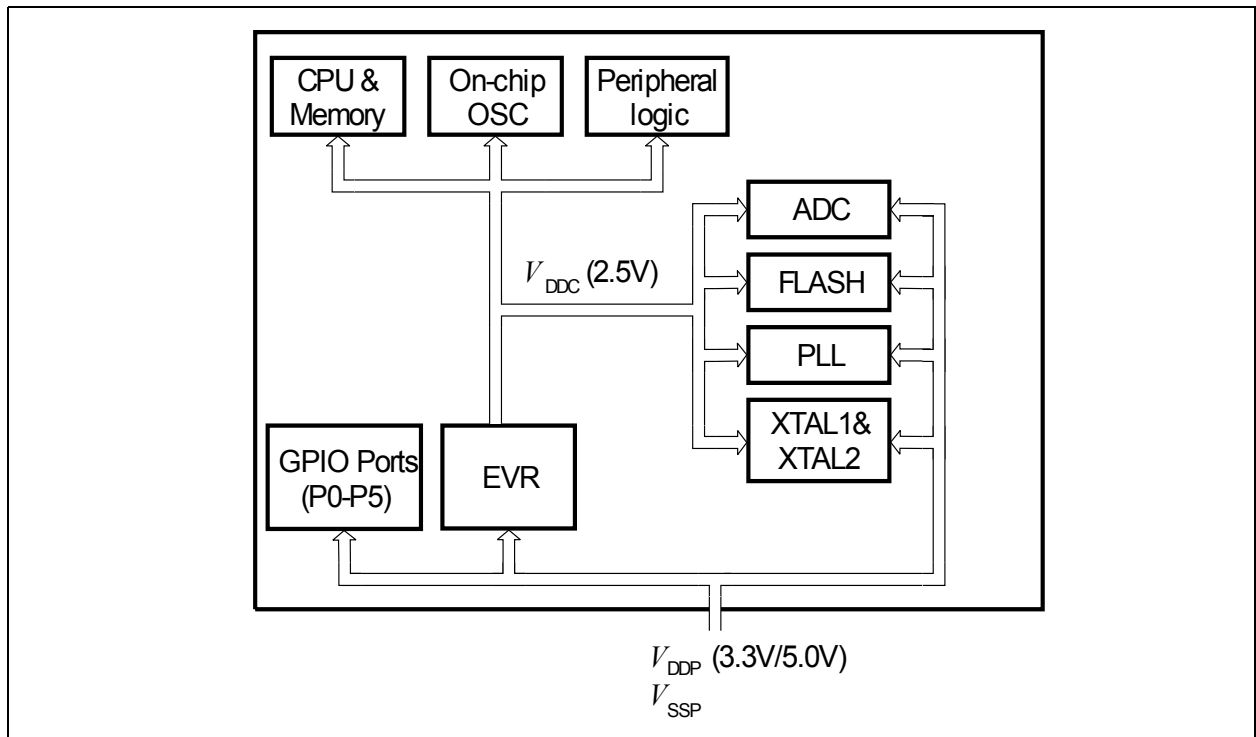


Figure 21 XC886/888 Power Supply System

EVR Features

- Input voltage (V_{DDP}): 3.3 V/5.0 V
- Output voltage (V_{DDC}): 2.5 V \pm 7.5%
- Low power voltage regulator provided in power-down mode
- V_{DDC} and V_{DDP} prewarning detection
- V_{DDC} brownout detection

Functional Description

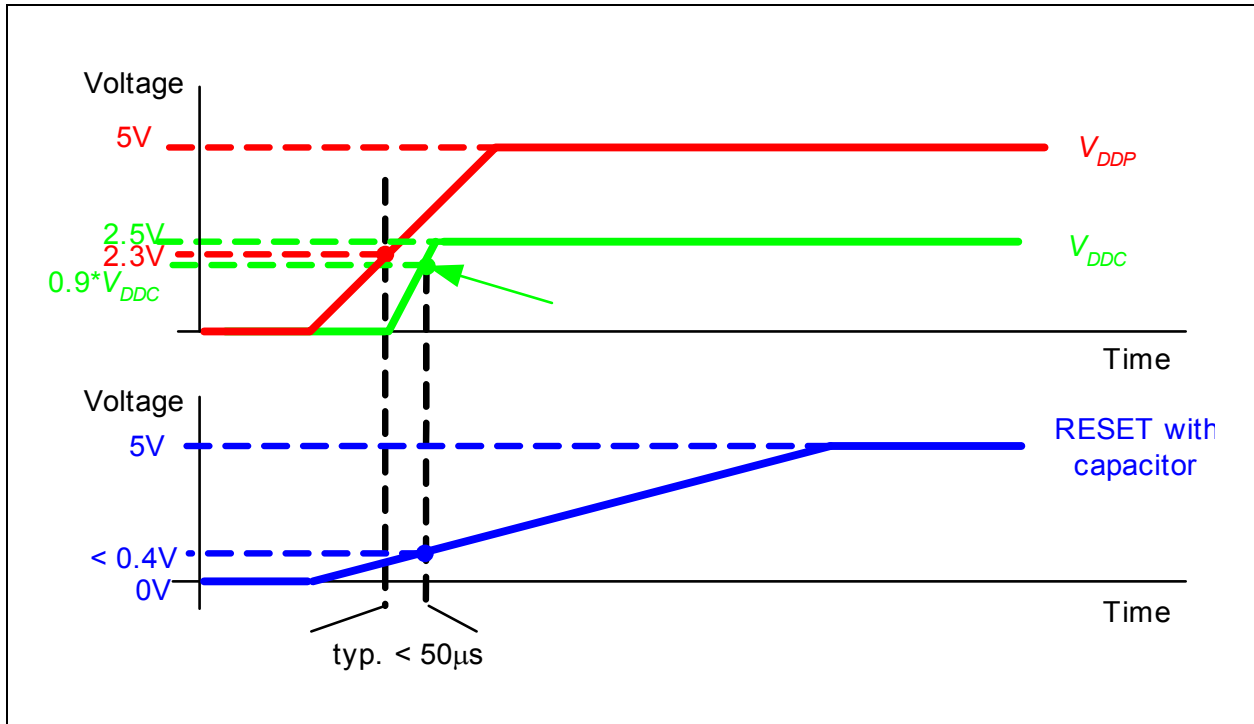


Figure 23 V_{DDP} , V_{DDC} and V_{RESET} during Power-on Reset

The second type of reset in XC886/888 is the hardware reset. This reset function can be used during normal operation or when the chip is in power-down mode. A reset input pin $\overline{\text{RESET}}$ is provided for the hardware reset.

The Watchdog Timer (WDT) module is also capable of resetting the device if it detects a malfunction in the system.

Another type of reset that needs to be detected is a reset while the device is in power-down mode (wake-up reset). While the contents of the static RAM are undefined after a power-on reset, they are well defined after a wake-up reset from power-down mode.

Functional Description

Table 25 shows the VCO range for the XC886/888.

Table 25 VCO Range

f_{VCOmin}	f_{VCOmax}	$f_{VCOFREEmin}$	$f_{VCOFREEmax}$	Unit
150	200	20	80	MHz
100	150	10	80	MHz

3.8.1 Recommended External Oscillator Circuits

The oscillator circuit, a Pierce oscillator, is designed to work with both, an external crystal oscillator or an external stable clock source. It basically consists of an inverting amplifier and a feedback element with XTAL1 as input, and XTAL2 as output.

When using a crystal, a proper external oscillator circuitry must be connected to both pins, XTAL1 and XTAL2. The crystal frequency can be within the range of 4 MHz to 12 MHz. Additionally, it is necessary to have two load capacitances C_{X1} and C_{X2} , and depending on the crystal type, a series resistor R_{X2} , to limit the current. A test resistor R_Q may be temporarily inserted to measure the oscillation allowance (negative resistance) of the oscillator circuitry. R_Q values are typically specified by the crystal vendor. The C_{X1} and C_{X2} values shown in **Figure 25** can be used as starting points for the negative resistance evaluation and for non-productive systems. The exact values and related operating range are dependent on the crystal frequency and have to be determined and optimized together with the crystal vendor using the negative resistance method. Oscillation measurement with the final target system is strongly recommended to verify the input amplitude at XTAL1 and to determine the actual oscillation allowance (margin negative resistance) for the oscillator-crystal system.

When using an external clock signal, the signal must be connected to XTAL1. XTAL2 is left open (unconnected).

The oscillator can also be used in combination with a ceramic resonator. The final circuitry must also be verified by the resonator vendor. **Figure 25** shows the recommended external oscillator circuitries for both operating modes, external crystal mode and external input clock mode.

Functional Description

- CAN functionality according to CAN specification V2.0 B active.
- Dedicated control registers are provided for each CAN node.
- A data transfer rate up to 1 MBaud is supported.
- Flexible and powerful message transfer control and error handling capabilities are implemented.
- Advanced CAN bus bit timing analysis and baud rate detection can be performed for each CAN node via the frame counter.
- Full-CAN functionality: A set of 32 message objects can be individually
 - allocated (assigned) to any CAN node
 - configured as transmit or receive object
 - setup to handle frames with 11-bit or 29-bit identifier
 - counted or assigned a timestamp via a frame counter
 - configured to remote monitoring mode
- Advanced Acceptance Filtering:
 - Each message object provides an individual acceptance mask to filter incoming frames.
 - A message object can be configured to accept only standard or only extended frames or to accept both standard and extended frames.
 - Message objects can be grouped into 4 priority classes.
 - The selection of the message to be transmitted first can be performed on the basis of frame identifier, IDE bit and RTR bit according to CAN arbitration rules.
- Advanced Message Object Functionality:
 - Message Objects can be combined to build FIFO message buffers of arbitrary size, which is only limited by the total number of message objects.
 - Message objects can be linked to form a gateway to automatically transfer frames between 2 different CAN buses. A single gateway can link any two CAN nodes. An arbitrary number of gateways may be defined.
- Advanced Data Management:
 - The Message objects are organized in double chained lists.
 - List reorganizations may be performed any time, even during full operation of the CAN nodes.
 - A powerful, command driven list controller manages the organization of the list structure and ensures consistency of the list.
 - Message FIFOs are based on the list structure and can easily be scaled in size during CAN operation.
 - Static Allocation Commands offer compatibility with TwinCAN applications, which are not list based.
- Advanced Interrupt Handling:
 - Up to 8 interrupt output lines are available. Most interrupt requests can be individually routed to one of the 8 interrupt output lines.
 - Message postprocessing notifications can be flexibly aggregated into a dedicated register field of 64 notification bits.

3.22 On-Chip Debug Support

The On-Chip Debug Support (OCDS) provides the basic functionality required for the software development and debugging of XC800-based systems.

The OCDS design is based on these principles:

- Use the built-in debug functionality of the XC800 Core
- Add a minimum of hardware overhead
- Provide support for most of the operations by a Monitor Program
- Use standard interfaces to communicate with the Host (a Debugger)

Features

- Set breakpoints on instruction address and on address range within the Program Memory
- Set breakpoints on internal RAM address range
- Support unlimited software breakpoints in Flash/RAM code region
- Process external breaks via JTAG and upon activating a dedicated pin
- Step through the program code

The OCDS functional blocks are shown in [Figure 37](#). The Monitor Mode Control (MMC) block at the center of OCDS system brings together control signals and supports the overall functionality. The MMC communicates with the XC800 Core, primarily via the Debug Interface, and also receives reset and clock signals.

After processing memory address and control signals from the core, the MMC provides proper access to the dedicated extra-memories: a Monitor ROM (holding the code) and a Monitor RAM (for work-data and Monitor-stack).

The OCDS system is accessed through the JTAG¹⁾, which is an interface dedicated exclusively for testing and debugging activities and is not normally used in an application. The dedicated MBC pin is used for external configuration and debugging control.

Note: All the debug functionality described here can normally be used only after XC886/888 has been started in OCDS mode.

1) The pins of the JTAG port can be assigned to either the primary port (Port 0) or either of the secondary ports (Ports 1 and 2/Port 5).

User must set the JTAG pins (TCK and TDI) as input during connection with the OCDS system.

Functional Description
3.23 Chip Identification Number

The XC886/888 identity (ID) register is located at Page 1 of address B3_H. The value of ID register is 09_H for Flash devices and 22_H for ROM devices. However, for easy identification of product variants, the Chip Identification Number, which is an unique number assigned to each product variant, is available. The differentiation is based on the product, variant type and device step information.

Two methods are provided to read a device's chip identification number:

- In-application subroutine, GET_CHIP_INFO
- Bootstrap loader (BSL) mode A

Table 36 lists the chip identification numbers of available XC886/888 Flash and ROM device variants.

Table 36 Chip Identification Number

Product Variant	Chip Identification Number		
	AA-Step	AB-Step	AC-Step
Flash Devices			
XC886CLM-8FFA 3V3	-	09500102 _H	0B500102 _H
XC888CLM-8FFA 3V3	-	09500103 _H	0B500103 _H
XC886LM-8FFA 3V3	-	09500122 _H	0B500122 _H
XC888LM-8FFA 3V3	-	09500123 _H	0B500123 _H
XC886CLM-6FFA 3V3	-	09551502 _H	0B551502 _H
XC888CLM-6FFA 3V3	-	09551503 _H	0B551503 _H
XC886LM-6FFA 3V3	-	09551522 _H	0B551522 _H
XC888LM-6FFA 3V3	-	09551523 _H	0B551523 _H
XC886CM-8FFA 3V3	-	09580102 _H	0B580102 _H
XC888CM-8FFA 3V3	-	09580103 _H	0B580103 _H
XC886C-8FFA 3V3	-	09580142 _H	0B580142 _H
XC888C-8FFA 3V3	-	09580143 _H	0B580143 _H
XC886-8FFA 3V3	-	09580162 _H	0B580162 _H
XC888-8FFA 3V3	-	09580163 _H	0B580163 _H
XC886CM-6FFA 3V3	-	095D1502 _H	0B5D1502 _H
XC888CM-6FFA 3V3	-	095D1503 _H	0B5D1503 _H
XC886C-6FFA 3V3	-	095D1542 _H	0B5D1542 _H
XC888C-6FFA 3V3	-	095D1543 _H	0B5D1543 _H

Functional Description

Table 36 **Chip Identification Number (cont'd)**

Product Variant	Chip Identification Number		
	AA-Step	AB-Step	AC-Step
XC886LM-6RFA 3V3	22411522 _H	-	-
XC888LM-6RFA 3V3	22411523 _H	-	-
XC886CM-8RFA 3V3	22480502 _H	-	-
XC888CM-8RFA 3V3	22480503 _H	-	-
XC886C-8RFA 3V3	22480542 _H	-	-
XC888C-8RFA 3V3	22480543 _H	-	-
XC886-8RFA 3V3	22480562 _H	-	-
XC888-8RFA 3V3	22480563 _H	-	-
XC886CM-6RFA 3V3	22491502 _H	-	-
XC888CM-6RFA 3V3	22491503 _H	-	-
XC886C-6RFA 3V3	22491542 _H	-	-
XC888C-6RFA 3V3	22491543 _H	-	-
XC886-6RFA 3V3	22491562 _H	-	-
XC888-6RFA 3V3	22491563 _H	-	-
XC886CLM-8RFA 5V	22800502 _H	-	-
XC888CLM-8RFA 5V	22800503 _H	-	-
XC886LM-8RFA 5V	22800522 _H	-	-
XC888LM-8RFA 5V	22800523 _H	-	-
XC886CLM-6RFA 5V	22811502 _H	-	-
XC888CLM-6RFA 5V	22811503 _H	-	-
XC886LM-6RFA 5V	22811522 _H	-	-
XC888LM-6RFA 5V	22811523 _H	-	-
XC886CM-8RFA 5V	22880502 _H	-	-
XC888CM-8RFA 5V	22880503 _H	-	-
XC886C-8RFA 5V	22880542 _H	-	-
XC888C-8RFA 5V	22880543 _H	-	-
XC886-8RFA 5V	22880562 _H	-	-
XC888-8RFA 5V	22880563 _H	-	-
XC886CM-6RFA 5V	22891502 _H	-	-

4 Electrical Parameters

Chapter 4 provides the characteristics of the electrical parameters which are implementation-specific for the XC886/888.

4.1 General Parameters

The general parameters are described here to aid the users in interpreting the parameters mainly in [Section 4.2](#) and [Section 4.3](#).

4.1.1 Parameter Interpretation

The parameters listed in this section represent partly the characteristics of the XC886/888 and partly its requirements on the system. To aid interpreting the parameters easily when evaluating them for a design, they are indicated by the abbreviations in the "Symbol" column:

- **CC**
These parameters indicate **C**ontroller **C**haracteristics, which are distinctive features of the XC886/888 and must be regarded for a system design.
- **SR**
These parameters indicate **S**ystem **R**equirements, which must be provided by the microcontroller system in which the XC886/888 is designed in.

Electrical Parameters

4.1.3 Operating Conditions

The following operating conditions must not be exceeded in order to ensure correct operation of the XC886/888. All parameters mentioned in the following table refer to these operating conditions, unless otherwise noted.

Table 37 Operating Condition Parameters

Parameter	Symbol	Limit Values		Unit	Notes/ Conditions
		min.	max.		
Digital power supply voltage	V_{DDP}	4.5	5.5	V	5V Device
Digital power supply voltage	V_{DDP}	3.0	3.6	V	3.3V Device
Digital ground voltage	V_{SS}	0		V	
Digital core supply voltage	V_{DDC}	2.3	2.7	V	
System Clock Frequency ¹⁾	f_{SYS}	88.8	103.2	MHz	
Ambient temperature	T_A	-40	85	°C	SAF- XC886/888...
		-40	125	°C	SAK- XC886/888...

1) f_{SYS} is the PLL output clock. During normal operating mode, CPU clock is $f_{SYS} / 4$. Please refer to [Figure 26](#) for detailed description.

Electrical Parameters
Table 38 Input/Output Characteristics (Operating Conditions apply) (cont'd)

Parameter	Symbol		Limit Values		Unit	Test Conditions
			min.	max.		
Input high voltage at XTAL1	V_{IHx}	SR	$0.7 \times V_{DDC}$	$V_{DDC} + 0.5$	V	
Pull-up current	I_{PU}	SR	–	-5	μA	$V_{IHP,min}$
			-50	–	μA	$V_{ILP,max}$
Pull-down current	I_{PD}	SR	–	5	μA	$V_{ILP,max}$
			50	–	μA	$V_{IHP,min}$
Input leakage current	I_{OZ1}	CC	-1	1	μA	$0 < V_{IN} < V_{DDP}$, $T_A \leq 125^\circ C^{2)}$
Input current at XTAL1	I_{ILx}	CC	- 10	10	μA	
Overload current on any pin	I_{OV}	SR	-5	5	mA	
Absolute sum of overload currents	$\Sigma I_{OV} $	SR	–	25	mA	³⁾
Voltage on any pin during V_{DDP} power off	V_{PO}	SR	–	0.3	V	⁴⁾
Maximum current per pin (excluding V_{DDP} and V_{SS})	I_M	SR SR	–	15	mA	
Maximum current for all pins (excluding V_{DDP} and V_{SS})	$\Sigma I_M $	SR	–	90	mA	
Maximum current into V_{DDP}	I_{MVDDP}	SR	–	120	mA	³⁾
Maximum current out of V_{SS}	I_{MVSS}	SR	–	120	mA	³⁾

1) Not subjected to production test, verified by design/characterization. Hysteresis is implemented to avoid meta stable states and switching due to internal ground bounce. It cannot be guaranteed that it suppresses switching due to external system noise.

2) An additional error current (I_{INJ}) will flow if an overload current flows through an adjacent pin. TMS pin and RESET pin have internal pull devices and are not included in the input leakage current characteristic.

3) Not subjected to production test, verified by design/characterization.

4) Not subjected to production test, verified by design/characterization. However, for applications with strict low power-down current requirements, it is mandatory that no active voltage source is supplied at any GPIO pin when V_{DDP} is powered off.

Electrical Parameters
Table 40 ADC Characteristics (Operating Conditions apply; $V_{DDP} = 5V$ Range)

Parameter	Symbol		Limit Values			Unit	Test Conditions/ Remarks
			min.	typ .	max.		
Overload current coupling factor for digital I/O pins	K_{OVD}	CC	–	–	5.0×10^{-3}	–	$I_{OV} > 0^{1)3)}$
			–	–	1.0×10^{-2}	–	$I_{OV} < 0^{1)3)}$
Switched capacitance at the reference voltage input	C_{AREFSW}	CC	–	10	20	pF	1)4)
Switched capacitance at the analog voltage inputs	C_{AINSW}	CC	–	5	7	pF	1)5)
Input resistance of the reference input	R_{AREF}	CC	–	1	2	k Ω	1)
Input resistance of the selected analog channel	R_{AIN}	CC	–	1	1.5	k Ω	1)

1) Not subjected to production test, verified by design/characterization

2) TUE is tested at $V_{AREF} = 5.0 V$, $V_{AGND} = 0 V$, $V_{DDP} = 5.0 V$.

3) An overload current (I_{OV}) through a pin injects a certain error current (I_{INJ}) into the adjacent pins. This error current adds to the respective pin's leakage current (I_{OZ}). The amount of error current depends on the overload current and is defined by the overload coupling factor K_{OV} . The polarity of the injected error current is inverse compared to the polarity of the overload current that produces it. The total current through a pin is $|I_{TOT}| = |I_{OZ1}| + (|I_{OV}| \times K_{OV})$. The additional error current may distort the input voltage on analog inputs.

4) This represents an equivalent switched capacitance. This capacitance is not switched to the reference voltage at once. Instead of this, smaller capacitances are successively switched to the reference voltage.

5) The sampling capacity of the conversion C-Network is pre-charged to $V_{AREF}/2$ before connecting the input to the C-Network. Because of the parasitic elements, the voltage measured at ANx is lower than $V_{AREF}/2$.

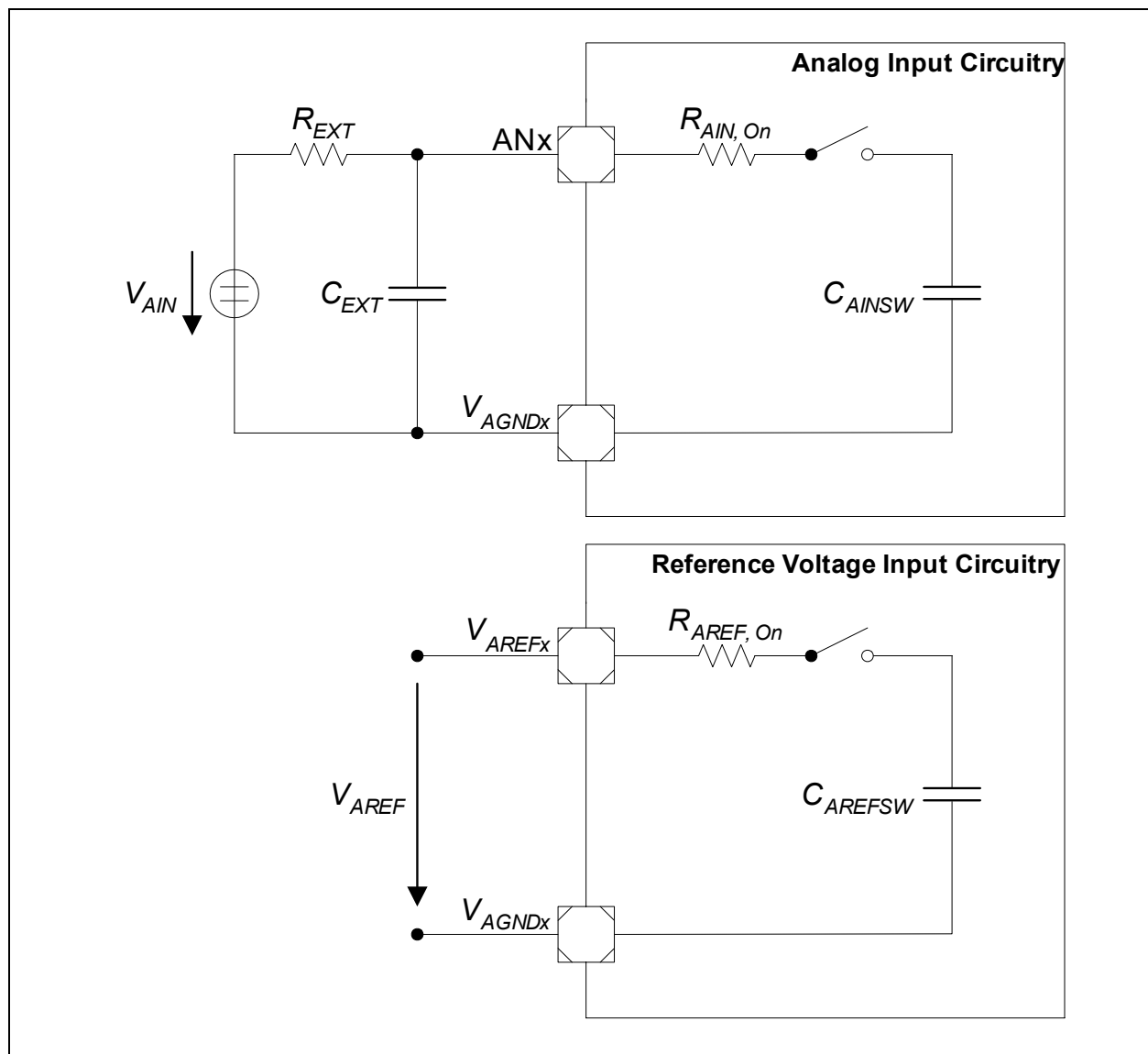


Figure 39 **ADC Input Circuits**

Electrical Parameters

Table 44 **Power Down Current (Operating Conditions apply; $V_{DDP} = 3.3V$ range)**

Parameter	Symbol	Limit Values		Unit	Test Condition
		typ. ¹⁾	max. ²⁾		
V_{DDP} = 3.3V Range					
Power-Down Mode	I_{PDP}	1	10	μA	T_A = + 25 °C ³⁾⁴⁾
		-	30	μA	T_A = + 85 °C ⁴⁾⁵⁾

1) The typical I_{PDP} values are measured at $V_{DDP} = 3.3\text{ V}$.

2) The maximum I_{PDP} values are measured at $V_{DDP} = 3.6\text{ V}$.

3) I_{PDP} has a maximum value of $200\text{ }\mu A$ at $T_A = + 125\text{ }^{\circ}C$.

4) I_{PDP} is measured with: $\overline{RESET} = V_{DDP}$, $V_{AGND} = V_{SS}$, $RXD/INT0 = V_{DDP}$; rest of the ports are programmed to be input with either internal pull devices enabled or driven externally to ensure no floating inputs.

5) Not subjected to production test, verified by design/characterization.

4.3.7 SSC Master Mode Timing

Table 51 provides the characteristics of the SSC timing in the XC886/888.

Table 51 SSC Master Mode Timing (Operating Conditions apply; CL = 50 pF)

Parameter	Symbol		Limit Values		Unit	Test Conditions
			min.	max.		
SCLK clock period	t_0	CC	$2 \cdot T_{SSC}$	–	ns	1)2)
MTSR delay from SCLK	t_1	CC	0	8	ns	2)
MRST setup to SCLK	t_2	SR	24	–	ns	2)
MRST hold from SCLK	t_3	SR	0	–	ns	2)

1) $T_{SSCmin} = T_{CPU} = 1/f_{CPU}$. When $f_{CPU} = 24$ MHz, $t_0 = 83.3$ ns. T_{CPU} is the CPU clock period.

2) Not all parameters are 100% tested, but are verified by design/characterization and test correlation.

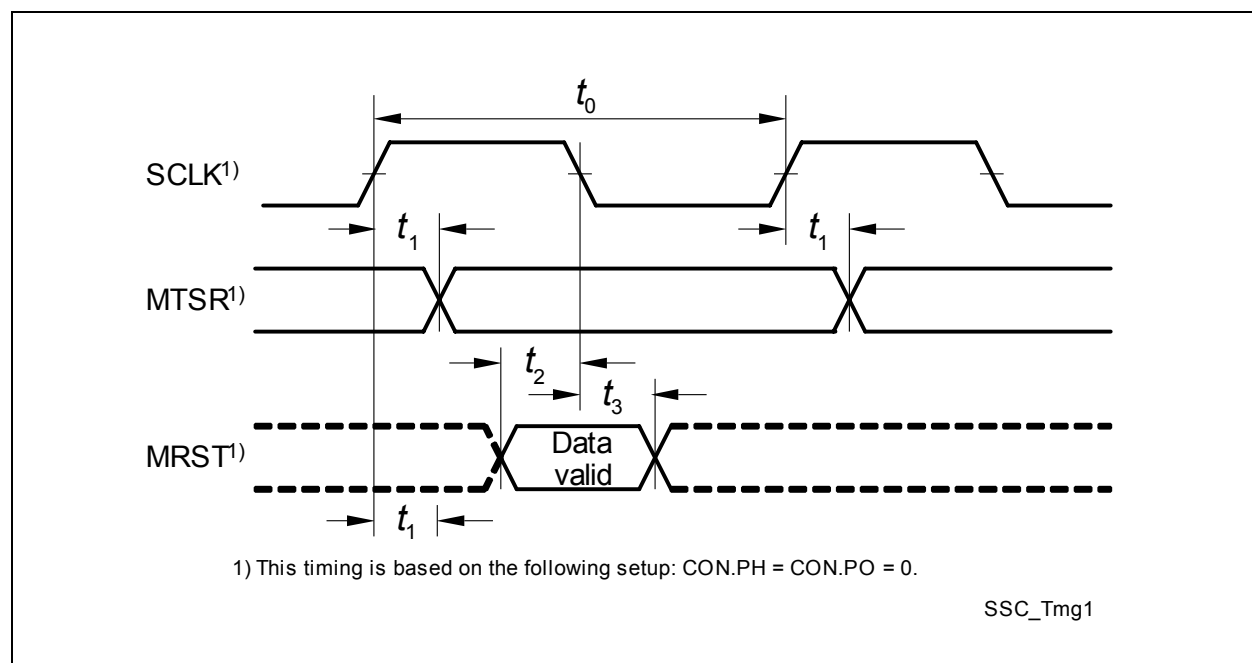


Figure 52 SSC Master Mode Timing